




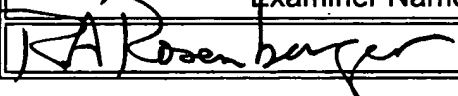


ELECTRONIC INFORMATION DISCLOSURE STATEMENT

Electronic Version v18
Stylesheet Version v18.0

Title of Invention	SYSTEMS AND METHODS FOR MULTI-DIMENSIONAL METROLOGY AND/OR INSPECTION OF A SPECIMEN						
Application Number: 10/688503							
Confirmation Number: 1964							
First Named Applicant: Tim Wihl							
Attorney Docket Number: 5589-04301							
Search string: (5999266 or 6181472 or 6268923 or 20020018118).pn.							
US Patent Documents							
Note: Applicant is not required to submit a paper copy of cited US Patent Documents							
init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	5999266	1999-12-07	Takahashi et al.			
	2	6181472	2001-01-30	Liu			
	3	6268923	2001-07-31	Michniewicz et al.			
US Published Applications							
Note: Applicant is not required to submit a paper copy of cited US Published Applications							
init	Cite.No.	Pub. No.	Date	Applicant	Kind	Class	Subclass
	1	20020018118	2002-02-14	Coulombe et al.			
Signature							
Examiner Name				Date			
				2/28/2006			

